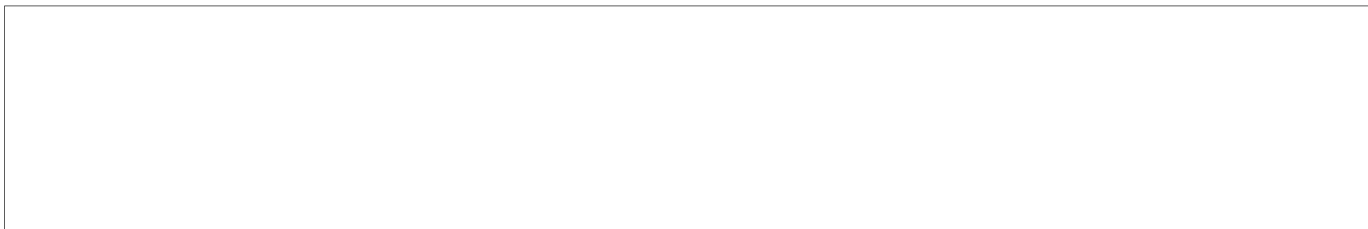


**SECRET**

25X1



February 10, 1971

Attention: John C.

Dear John:

Enclosed please find three copies of Activity Summary  
No. 27,  2201201-AS-27.

Sincerely,



25X1

Senior Staff Scientist

PSC/c  
Enclosure

THIS DOCUMENT UNCLASSIFIED WHEN  
SEPARATED FROM CLASSIFIED ATTACHMENT

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**SECRET**Copy No. a of a-d

25X1

February 10, 1971

## ACTIVITY SUMMARY

To: John C.  
From: [redacted] 25X1  
Subject: Activity Summary  
Facility Visit, Contract [redacted] 25X1  
Reference: [redacted] 2201201-AS-27 25X1  
Dates: 2,3 February 1971

On February 2 and 3, 1971 [redacted] visited the sponsor 25X1  
lab on Contract [redacted] The objectives of this visit were  
two-fold:

- (1) To aid data reduction of sinusoidal targets for OIM system characterization.
- (2) To review film material for the purpose of selecting targets for OIM applications to operational material.

These two objectives were emphasized during this trip. About fifty DP selections were made including low contrast, motion blurred and defocused imagery.

The program plan for the week of February 8, 1971, was left with John C. on February 3. A copy is attached to this activity summary.

GROUP 1

EXCLUDED FROM AUTOMATIC  
DOWNGRADING AND  
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## NOTICE

THIS MATERIAL CONTAINS INFORMATION AFFECTING THE NATIONAL DEFENSE OF THE UNITED STATES WITHIN THE MEANING OF THE ESPIONAGE LAWS, TITLE 18, USC, SECS. 793 AND 794, THE TRANSMISSION OR REVELATION OF WHICH IN ANY MANNER TO AN UNAUTHORIZED PERSON IS PROHIBITED BY LAW.

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25X1

The following trip is scheduled for February 8,9 by [ ] for initial tasks in implementing phase plate fabrication. This will be followed by another visit now planned 25X1 for February 16, 17. OIM of selected operational imagery is planned for the week of February 22 by [ ]

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## Program Plan

To: John C.

From:

Subject: Program Plan for week of 8 Feb, 1971

Date: 3 Feb, 1971

During the past two days we have pursued further data collection for characterization of system response and have scanned (visually) 12 rolls of RP material for selection of imagery for high frequency OIM. There are continuing tasks; concomitant with these we are initiating fabrication techniques for phase plates utilizing emulsion relief imagery on bleached High Resolution Plates. These three directions are the primary subjects for activity during the week beginning 8 February.

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The following items are therefore scheduled in accordance to the Program Schedule previously generated and the specific tasks at hand.

1. Continue data reduction and evaluation. Double check micro-d scan accuracy. Review reduced data for "reasonableness" as a rough check against anomalies in data collection or data reduction. When all data is reduced start plotting information, especially with objective of presenting system frequency response for correlation to that predicted.
2. Obtain DP's of imagery selected. Get one role on priority bases, others within three weeks. We want to schedule further OIM on week

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of 8 Feb.

25X1 3. [ ] will visit lab on Mon. + Tues, 8-9 Feb., for implementation of accurate techniques for generating phase relief image plates. This will also include methods for their measurement.

25X1 4. [ ] are scheduling a three day OIM session with all DP's that have been selected. The dates include 24-26 Feb., 1971. This schedule will allow us to emphasize the operational OIM applications discussed above.

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